

#### Welcome to E-XFL.COM

#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

## Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

E·XFI

Product Status	Active
Core Processor	AVR
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	CANbus, Ethernet, I <sup>2</sup> C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I <sup>2</sup> S, POR, PWM, WDT
Number of I/O	81
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x12b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/at32uc3c1512c-azr

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

# AT32UC3C

- One 4-Channel 20-bit Pulse Width Modulation Controller (PWM)
  - Complementary outputs, with Dead Time Insertion
  - Output Override and Fault Protection
- Two Quadrature Decoders
- One 16-channel 12-bit Pipelined Analog-To-Digital Converter (ADC)
  - Dual Sample and Hold Capability Allowing 2 Synchronous Conversions
  - Single-Ended and Differential Channels, Window Function
- Two 12-bit Digital-To-Analog Converters (DAC), with Dual Output Sample System
- Four Analog Comparators
- Six 16-bit Timer/Counter (TC) Channels
  - External Clock Inputs, PWM, Capture and Various Counting Capabilities
- One Peripheral Event Controller
  - Trigger Actions in Peripherals Depending on Events Generated from Peripherals or from Input Pins
  - Deterministic Trigger
  - 34 Events and 22 Event Actions
- Five Universal Synchronous/Asynchronous Receiver/Transmitters (USART)
  - Independent Baudrate Generator, Support for SPI, LIN, IrDA and ISO7816 interfaces
  - Support for Hardware Handshaking, RS485 Interfaces and Modem Line
- Two Master/Slave Serial Peripheral Interfaces (SPI) with Chip Select Signals
- One Inter-IC Sound (I2S) Controller
  - Compliant with I2S Bus Specification
  - Time Division Multiplexed mode
- Three Master and Three Slave Two-Wire Interfaces (TWI), 400kbit/s I<sup>2</sup>C-compatible
- QTouch<sup>®</sup> Library Support
  - Capacitive Touch Buttons, Sliders, and Wheels
  - QTouch<sup>®</sup> and QMatrix<sup>®</sup> Acquisition
- On-Chip Non-intrusive Debug System
  - Nexus Class 2+, Runtime Control, Non-Intrusive Data and Program Trace
  - aWire<sup>™</sup> single-pin programming trace and debug interface muxed with reset pin
  - NanoTrace<sup>™</sup> provides trace capabilities through JTAG or aWire interface
- 3 package options
  - 64-pin QFN/TQFP (45 GPIO pins)
  - 100-pin TQFP (81 GPIO pins)
  - 144-pin LQFP (123 GPIO pins)
- Two operating voltage ranges:
  - Single 5V Power Supply
  - Single 3.3V Power Supply

# 2.2 Configuration Summary

 Table 2-1.
 Configuration Summary

Feature	AT32UC3C0512C	AT32UC3C1512C	AT32UC3C2512C			
Flash	512 KB	512 KB	512 KB			
SRAM	64KB	64KB	64KB			
HSB RAM	4 KB					
EBI	1	0	0			
GPIO	123	81	45			
External Interrupts	8	8	8			
TWI	3	3	2			
USART	5	5	4			
Peripheral DMA Channels	16	16	16			
Peripheral Event System	1	1	1			
SPI	2	2	1			
CAN channels	2	2	2			
USB	1	1	1			
Ethernet MAC 10/100	1	1	1			
	RMII/MII	RMII/MII	RMII only			
12S	1	1	1			
Asynchronous Timers	1	1	1			
Timer/Counter Channels	6	6	3			
PWM channels	4x2					
QDEC	2	2	1			
Frequency Meter	1					
Watchdog Timer	1					
Power Manager	1					
Oscillators	PLL 80-240 MHz (PLL0/PLL1) Crystal Oscillator 0.4-20 MHz (OSC0) Crystal Oscillator 32 KHz (OSC32K) RC Oscillator 115 kHz (RCSYS) RC Oscillator 8 MHz (RC8M) RC Oscillator 120 MHz (RC120M)					
	0.4-20 Mi	Hz (OSC1)	-			
12-bit ADC	1 16	1	1   11			
12-hit DAC	1	1	1			
number of channels	4	4	2			
Analog Comparators	4	4	2			
JTAG	1					



## 3. Package and Pinout

## 3.1 Package

The device pins are multiplexed with peripheral functions as described in Table 3-1 on page 11.





Note: on QFN packages, the exposed pad is unconnected.



 Table 3-1.
 GPIO Controller Function Multiplexing

TQFP				G			GPIO function					
/ 	TOEP			P		Pin						
64	100	144	PIN	0	Supply	(1)	Α	в	с	D	Е	F
		14	PB11	43	VDDIO1	x1/x2	USART1 - DSR	SPI0 - MISO	PWM - PWMH[1]			
		15	PB12	44	VDDIO1	x1/x2	USART1 - DCD	SPI0 - SCK	PWM - PWML[2]			
		16	PB13	45	VDDIO1	x1/x2	USART1 - RI	SPI0 - NPCS[0]	PWM - PWMH[2]		MACB - RX_ER	
		17	PB14	46	VDDIO1	x1/x2	USART1 - RTS	SPI0 - NPCS[1]	PWM - PWML[3]		MACB - MDC	
		18	PB15	47	VDDIO1	x1/x2	USART1 - CTS	USART1 - CLK	PWM - PWMH[3]		MACB - MDIO	
		19	PB16	48	VDDIO1	x1/x2	USART1 - RXD	SPI0 - NPCS[2]	PWM - EXT_ FAULTS[0]		CANIF - RXLINE[0]	
		20	PB17	49	VDDIO1	x1/x2	USART1 - TXD	SPI0 - NPCS[3]	PWM - EXT_ FAULTS[1]		CANIF - TXLINE[0]	
		57	PB18	50	VDDIO2	x1/x2	TC0 - CLK2		EIC - EXTINT[4]			
	42	58	PB19	51	VDDIO2	x1/x2	TC0 - A0	SPI1 - MOSI	IISC - ISDO		MACB - CRS	
	43	59	PB20	52	VDDIO2	x1/x2	TC0 - B0	SPI1 - MISO	IISC - ISDI	ACIFA1 - ACAOUT	MACB - COL	
	44	60	PB21	53	VDDIO2	x2/x4	TC0 - CLK1	SPI1 - SCK	IISC - IMCK	ACIFA1 - ACBOUT	MACB - RXD[2]	
	45	61	PB22	54	VDDIO2	x1/x2	TC0 - A1	SPI1 - NPCS[3]	IISC - ISCK	SCIF - GCLK[0]	MACB - RXD[3]	
	46	62	PB23	55	VDDIO2	x1/x2	TC0 - B1	SPI1 - NPCS[2]	IISC - IWS	SCIF - GCLK[1]	MACB - RX_CLK	
		63	PB24	56	VDDIO2	x1/x2	TC0 - CLK0	SPI1 - NPCS[1]				
		64	PB25	57	VDDIO2	x1/x2	TC0 - A2	SPI1 - NPCS[0]	PEVC - PAD_EVT [8]			
		65	PB26	58	VDDIO2	x2/x4	TC0 - B2	SPI1 - SCK	PEVC - PAD_EVT [9]		MACB - TX_EN	
		66	PB27	59	VDDIO2	x1/x2	QDEC0 - QEPA	SPI1 - MISO	PEVC - PAD_EVT [10]	TC1 - CLK0	MACB - TXD[0]	
		67	PB28	60	VDDIO2	x1/x2	QDEC0 - QEPB	SPI1 - MOSI	PEVC - PAD_EVT [11]	TC1 - B0	MACB - TXD[1]	
		68	PB29	61	VDDIO2	x1/x2	QDEC0 - QEPI	SPI0 - NPCS[0]	PEVC - PAD_EVT [12]	TC1 - A0		
31	47	69	PB30	62	VDDIO2	x1						
32	48	70	PB31	63	VDDIO2	x1						
	49	71	PC00	64	VDDIO2	x1/x2	USBC - ID	SPI0 - NPCS[1]	USART2 - CTS	TC1 - B2	CANIF - TXLINE[1]	
	50	72	PC01	65	VDDIO2	x1/x2	USBC - VBOF	SPI0 - NPCS[2]	USART2 - RTS	TC1 - A2	CANIF - RXLINE[1]	



Table 3-1.	GPIO Controller Function Multiplexing
------------	---------------------------------------

TQFP				G			GPIO function					
/ QFN 64	TQFP 100	LQFP 144	PIN	P I O	Supply	Pin Type (1)	А	в	с	D	E	F
	72	97	PC24	88	VDDIO3	x1/x2	QDEC1 - QEPA	CANIF - TXLINE[1]	EBI - DATA[5]	PEVC - PAD_EVT [4]		
		98	PC25	89	VDDIO3	x1/x2		TC1 - CLK2	EBI - DATA[6]	SCIF - GCLK[0]	USART4 - TXD	
		99	PC26	90	VDDIO3	x1/x2	QDEC1 - QEPI	TC1 - B2	EBI - DATA[7]	SCIF - GCLK[1]	USART4 - RXD	
		100	PC27	91	VDDIO3	x1/x2		TC1 - A2	EBI - DATA[8]	EIC - EXTINT[0]	USART4 - CTS	
		101	PC28	92	VDDIO3	x1/x2	SPI1 - NPCS[3]	TC1 - CLK1	EBI - DATA[9]		USART4 - RTS	
		102	PC29	93	VDDIO3	x1/x2	SPI0 - NPCS[1]	TC1 - B1	EBI - DATA[10]			
		105	PC30	94	VDDIO3	x1/x2	SPI0 - NPCS[2]	TC1 - A1	EBI - DATA[11]			
	73	106	PC31	95	VDDIO3	x1/x2	SPI0 - NPCS[3]	TC1 - B0	EBI - DATA[12]	PEVC - PAD_EVT [5]	USART4 - CLK	
47	74	107	PD00	96	VDDIO3	x1/x2	SPIO - MOSI	TC1 - CLK0	EBI - DATA[13]	QDEC0 - QEPI	USART0 - TXD	
48	75	108	PD01	97	VDDIO3	x1/x2	SPI0 - MISO	TC1 - A0	EBI - DATA[14]	TC0 - CLK1	USART0 - RXD	
49	76	109	PD02	98	VDDIO3	x2/x4	SPI0 - SCK	TC0 - CLK2	EBI - DATA[15]	QDEC0 - QEPA		
50	77	110	PD03	99	VDDIO3	x1/x2	SPI0 - NPCS[0]	TC0 - B2	EBI - ADDR[0]	QDEC0 - QEPB		
		111	PD04	100	VDDIO3	x1/x2	SPI0 - MOSI		EBI - ADDR[1]			
		112	PD05	101	VDDIO3	x1/x2	SPI0 - MISO		EBI - ADDR[2]			
		113	PD06	102	VDDIO3	x2/x4	SPI0 - SCK		EBI - ADDR[3]			
	78	114	PD07	103	VDDIO3	x1/x2	USART1 - DTR	EIC - EXTINT[5]	EBI - ADDR[4]	QDEC0 - QEPI	USART4 - TXD	
	79	115	PD08	104	VDDIO3	x1/x2	USART1 - DSR	EIC - EXTINT[6]	EBI - ADDR[5]	TC1 - CLK2	USART4 - RXD	
	80	116	PD09	105	VDDIO3	x1/x2	USART1 - DCD	CANIF - RXLINE[0]	EBI - ADDR[6]	QDEC0 - QEPA	USART4 - CTS	
	81	117	PD10	106	VDDIO3	x1/x2	USART1 - RI	CANIF - TXLINE[0]	EBI - ADDR[7]	QDEC0 - QEPB	USART4 - RTS	
53	84	120	PD11	107	VDDIO3	x1/x2	USART1 - TXD	USBC - ID	EBI - ADDR[8]	PEVC - PAD_EVT [6]	MACB - TXD[0]	
54	85	121	PD12	108	VDDIO3	x1/x2	USART1 - RXD	USBC - VBOF	EBI - ADDR[9]	PEVC - PAD_EVT [7]	MACB - TXD[1]	
55	86	122	PD13	109	VDDIO3	x2/x4	USART1 - CTS	USART1 - CLK	EBI - SDCK	PEVC - PAD_EVT [8]	MACB - RXD[0]	
56	87	123	PD14	110	VDDIO3	x1/x2	USART1 - RTS	EIC - EXTINT[7]	EBI - ADDR[10]	PEVC - PAD_EVT [9]	MACB - RXD[1]	



## **Table 3-7.**Signal Description List

Signal Name	Function	Туре	Active Level	Comments
DP	USB Device Port Data +	Analog		
VBUS	USB VBUS Monitor and OTG Negociation	Analog Input		
ID	ID Pin of the USB Bus	Input		
VBOF	USB VBUS On/off: bus power control port	output		

## 3.4 I/O Line Considerations

## 3.4.1 JTAG pins

The JTAG is enabled if TCK is low while the RESET\_N pin is released. The TCK, TMS, and TDI pins have pull-up resistors when JTAG is enabled. The TCK pin always have pull-up enabled during reset. The TDO pin is an output, driven at VDDIO1, and has no pull-up resistor. The JTAG pins can be used as GPIO pins and muxed with peripherals when the JTAG is disabled. Please refer to Section 3.2.4 for the JTAG port connections.

#### 3.4.2 RESET\_N pin

The RESET\_N pin integrates a pull-up resistor to VDDIO1. As the product integrates a power-on reset cell, the RESET\_N pin can be left unconnected in case no reset from the system needs to be applied to the product.

The RESET\_N pin is also used for the aWire debug protocol. When the pin is used for debugging, it must not be driven by external circuitry.

#### 3.4.3 TWI pins

When these pins are used for TWI, the pins are open-drain outputs with slew-rate limitation and inputs with inputs with spike-filtering. When used as GPIO-pins or used for other peripherals, the pins have the same characteristics as GPIO pins.

#### 3.4.4 GPIO pins

All I/O lines integrate programmable pull-up and pull-down resistors. Most I/O lines integrate drive strength control, see Table 3-1. Programming of this pull-up and pull-down resistor or this drive strength is performed independently for each I/O line through the GPIO Controllers.

After reset, I/O lines default as inputs with pull-up/pull-down resistors disabled. After reset, output drive strength is configured to the lowest value to reduce global EMI of the device.

When the I/O line is configured as analog function (ADC I/O, AC inputs, DAC I/O), the pull-up and pull-down resistors are automatically disabled.



## 4.3.2.5 Unaligned Reference Handling

AVR32UC does not support unaligned accesses, except for doubleword accesses. AVR32UC is able to perform word-aligned *st.d* and *ld.d*. Any other unaligned memory access will cause an address exception. Doubleword-sized accesses with word-aligned pointers will automatically be performed as two word-sized accesses.

The following table shows the instructions with support for unaligned addresses. All other instructions require aligned addresses.

Instruction	Supported Alignment
ld.d	Word
st.d	Word

Table 4-1.Instructions with	Unaligned	Reference	Support
-----------------------------	-----------	-----------	---------

## 4.3.2.6 Unimplemented Instructions

The following instructions are unimplemented in AVR32UC, and will cause an Unimplemented Instruction Exception if executed:

- All SIMD instructions
- All coprocessor instructions if no coprocessors are present
- retj, incjosp, popjc, pushjc
- tlbr, tlbs, tlbw
- cache

## 4.3.2.7 CPU and Architecture Revision

Three major revisions of the AVR32UC CPU currently exist. The device described in this datasheet uses CPU revision 3.

The Architecture Revision field in the CONFIG0 system register identifies which architecture revision is implemented in a specific device.

AVR32UC CPU revision 3 is fully backward-compatible with revisions 1 and 2, ie. code compiled for revision 1 or 2 is binary-compatible with revision 3 CPUs.



Debug state can be entered as described in the AVR32UC Technical Reference Manual.

Debug state is exited by the *retd* instruction.

#### 4.4.3.3 Secure State

The AVR32 can be set in a secure state, that allows a part of the code to execute in a state with higher security levels. The rest of the code can not access resources reserved for this secure code. Secure State is used to implement FlashVault technology. Refer to the *AVR32UC Technical Reference Manual* for details.

## 4.4.4 System Registers

The system registers are placed outside of the virtual memory space, and are only accessible using the privileged *mfsr* and *mtsr* instructions. The table below lists the system registers specified in the AVR32 architecture, some of which are unused in AVR32UC. The programmer is responsible for maintaining correct sequencing of any instructions following a *mtsr* instruction. For detail on the system registers, refer to the *AVR32UC Technical Reference Manual*.

Reg #	Address	Name	Function
0	0	SR	Status Register
1	4	EVBA	Exception Vector Base Address
2	8	ACBA	Application Call Base Address
3	12	CPUCR	CPU Control Register
4	16	ECR	Exception Cause Register
5	20	RSR_SUP	Unused in AVR32UC
6	24	RSR_INT0	Unused in AVR32UC
7	28	RSR_INT1	Unused in AVR32UC
8	32	RSR_INT2	Unused in AVR32UC
9	36	RSR_INT3	Unused in AVR32UC
10	40	RSR_EX	Unused in AVR32UC
11	44	RSR_NMI	Unused in AVR32UC
12	48	RSR_DBG	Return Status Register for Debug mode
13	52	RAR_SUP	Unused in AVR32UC
14	56	RAR_INT0	Unused in AVR32UC
15	60	RAR_INT1	Unused in AVR32UC
16	64	RAR_INT2	Unused in AVR32UC
17	68	RAR_INT3	Unused in AVR32UC
18	72	RAR_EX	Unused in AVR32UC
19	76	RAR_NMI	Unused in AVR32UC
20	80	RAR_DBG	Return Address Register for Debug mode
21	84	JECR	Unused in AVR32UC
22	88	JOSP	Unused in AVR32UC
23	92	JAVA_LV0	Unused in AVR32UC

Table 4-3. System Registers



## 6. Supply and Startup Considerations

## 6.1 Supply Considerations

## 6.1.1 Power Supplies

The AT32UC3C has several types of power supply pins:

- VDDIO pins (VDDIO1, VDDIO2, VDDIO3): Power I/O lines. Two voltage ranges are available: 5V or 3.3V nominal. The VDDIO pins should be connected together.
- VDDANA: Powers the Analog part of the device (Analog I/Os, ADC, ACs, DACs). 2 voltage ranges available: 5V or 3.3V nominal.
- VDDIN\_5: Input voltage for the 1.8V and 3.3V regulators. Two Voltage ranges are available: 5V or 3.3V nominal.
- VDDIN\_33:
  - USB I/O power supply
  - if the device is 3.3V powered: Input voltage, voltage is 3.3V nominal.
  - if the device is 5V powered: stabilization for the 3.3V voltage regulator, requires external capacitors
- VDDCORE: Stabilization for the 1.8V voltage regulator, requires external capacitors.
- GNDCORE: Ground pins for the voltage regulators and the core.
- GNDANA: Ground pin for Analog part of the design
- GNDPLL: Ground pin for the PLLs
- GNDIO pins (GNDIO1, GNDIO2, GNDIO3): Ground pins for the I/O lines. The GNDIO pins should be connected together.

See "Electrical Characteristics" on page 49 for power consumption on the various supply pins.

For decoupling recommendations for the different power supplies, please refer to the schematic checklist.

## 6.1.2 Voltage Regulators

The AT32UC3C embeds two voltage regulators:

- One 1.8V internal regulator that converts from VDDIN\_5 to 1.8V. The regulator supplies the output voltage on VDDCORE.
- One 3.3V internal regulator that converts from VDDIN\_5 to 3.3V. The regulator supplies the USB pads on VDDIN\_33. If the USB is not used or if VDDIN\_5 is within the 3V range, the 3.3V regulator can be disabled through the VREG33CTL field of the VREGCTRL SCIF register.

## 6.1.3 Regulators Connection

The AT32UC3C supports two power supply configurations.

- 5V single supply mode
- 3.3V single supply mode

## 6.1.3.1 5V Single Supply Mode

In 5V single supply mode, the 1.8V internal regulator is connected to the 5V source (VDDIN\_5 pin) and its output feeds VDDCORE.



## 7. Electrical Characteristics

## 7.1 Absolute Maximum Ratings\*

Operating temperature40°C to +125°C
Storage temperature
Voltage on any pin except DM/DP/VBUS with respect to ground0.3V to ${\rm V_{VDD}}^{(1)}{\rm +0.3V}$
Voltage on DM/DP with respect to ground0.3V to +3.6V
Voltage on VBUS with respect to ground0.3V to +5.5V
Maximum operating voltage (VDDIN_5) 5.5V
Maximum operating voltage (VDDIO1, VDDIO2, VDDIO3, VDDANA)
Maximum operating voltage (VDDIN_33) 3.6V
Total DC output current on all I/O pins- VDDIO1 40 mA
Total DC output current on all I/O pins- VDDIO2 40 mA
Total DC output current on all I/O pins- VDDIO3 40 mA
Total DC output current on all I/O pins- VDDANA 40 mA

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Notes: 1. V<sub>VDD</sub> corresponds to either V<sub>VDDIO1</sub>, V<sub>VDDIO2</sub>, V<sub>VDDIO3</sub>, or V<sub>VDDANA</sub>, depending on the supply for the pin. Refer to Section 3-1 on page 11 for details.

## 7.2 Supply Characteristics

The following characteristics are applicable to the operating temperature range:  $T_A = -40$ °C to 125°C, unless otherwise specified and are valid for a junction temperature up to  $T_J = 145$ °C. Please refer to Section 6. "Supply and Startup Considerations" on page 45.

				Voltage	
Symbol	Parameter	Condition	Min	Мах	Unit
V	DC auguly internal regulators	3V range	3.0	3.6	N
V <sub>VDDIN_5</sub>	DC supply internal regulators	5V range	4.5	5.5	V
V <sub>VDDIN_33</sub>	DC supply USB I/O	only in 3V range	3.0	3.6	V
	DC supply peripheral I/O and	3V range	3.0	3.6	
V <sub>VDDANA</sub>	analog part	5V range	4.5	5.5	V
V <sub>VDDIO1</sub>		3V range	3.0	3.6	
V <sub>VDDIO2</sub> V <sub>VDDIO2</sub>	DC supply peripheral I/O	5V range	4.5	5.5	V

Table 7-1. Supply Characteristics



## Table 7-2. Supply Rise Rates and Order

			Rise Rate				
Symbol	Parameter	Min	Мах	Comment			
V <sub>VDDIN_5</sub>	DC supply internal 3.3V regulator	0.01 V/ms	1.25 V/us				
V <sub>VDDIN_33</sub>	DC supply internal 1.8V regulator	0.01 V/ms	1.25 V/us				
V <sub>VDDIO1</sub> V <sub>VDDIO2</sub> V <sub>VDDIO3</sub>	DC supply peripheral I/O	0.01 V/ms	1.25 V/us	Rise after or at the same time as VDDIN_5, VDDIN_33			
V <sub>VDDANA</sub>	DC supply peripheral I/O and analog part	0.01 V/ms	1.25 V/us	Rise after or at the same time as VDDIN_5, VDDIN_33			

## 7.3 Maximum Clock Frequencies

These parameters are given in the following conditions:

- V<sub>VDDCORE</sub> > 1.85V
- Temperature = -40°C to 125°C

Table 7-3.	Clock Frequencies
------------	-------------------

Symbol	Parameter	Conditions	Min	Max	Units
f <sub>CPU</sub>	CPU clock frequency			50	MHz
f <sub>PBA</sub>	PBA clock frequency			50	MHz
f <sub>PBB</sub>	PBB clock frequency			50	MHz
f <sub>PBC</sub>	PBC clock frequency			50	MHz
f <sub>GCLK0</sub>	GCLK0 clock frequency	Generic clock for USBC		50 <sup>(1)</sup>	MHz
f <sub>GCLK1</sub>	GCLK1 clock frequency	Generic clock for CANIF		66 <sup>(1)</sup>	MHz
f <sub>GCLK2</sub>	GCLK2 clock frequency	Generic clock for AST		80 <sup>(1)</sup>	MHz
f <sub>GCLK4</sub>	GCLK4 clock frequency	Generic clock for PWM		120 <sup>(1)</sup>	MHz
f <sub>GCLK11</sub>	GCLK11 clock frequency	Generic clock for IISC		50 <sup>(1)</sup>	MHz

Note: 1. These values are based on simulation and characterization of other AVR microcontrollers manufactured in the same process technology. These values are not covered by test limits in production.

## 7.4 Power Consumption

The values in Table 7-4 are measured values of power consumption under the following conditions, except where noted:

- Operating conditions core supply (Figure 7-1)
  - V<sub>VDDIN\_5</sub> = V<sub>VDDIN\_33</sub> = 3.3V
  - $V_{VDDCORE} = 1.85V$ , supplied by the internal regulator
  - V<sub>VDDIO1</sub> = V<sub>VDDIO2</sub> = V<sub>VDDIO3</sub> = 3.3V
  - $V_{VDDANA} = 3.3V$



## 7.5 I/O Pin Characteristics

Table 7-6.	Normal I/O Pin Characteristics <sup>(1)</sup>

Symbol	Parameter	Condition		Min	Тур	Max	Units
D	P Pull un registance			5		26	kOhm
R <sub>PULLUP</sub>	Pull-up resistance	V <sub>VDD</sub> = 5V		5		16	kOhm
R <sub>PULLDOWN</sub>	Pull-down resistance			2		16	kOhm
N	Input low-level	$V_{VDD} = 3V$				0.3*V <sub>VDDIO</sub>	<i>\</i> /
VIL	voltage	$V_{VDD} = 4.5V$				0.3*V <sub>VDDIO</sub>	V
M	Input high-level	$V_{VDD} = 3.6V$		0.7*V <sub>VDDIO</sub>			V
vін	voltage	$V_{VDD} = 5.5V$		0.7*V <sub>VDDIO</sub>			V
		I <sub>OL</sub> = -3.5mA,	pin drive x1 <sup>(2)</sup>				
V <sub>OL</sub>	Output low-level	I <sub>OL</sub> = -7mA, p	in drive x2 <sup>(2)</sup>			0.5	V
	, enage	I <sub>OL</sub> = -14mA,	pin drive x4 <sup>(2)</sup>				
		I <sub>OH</sub> = 3.5mA,	pin drive x1 <sup>(2)</sup>				
V <sub>OH</sub>	Output high-level	$I_{OH} = 7 \text{ mA}$ , pin drive x2 <sup>(2)</sup>		V <sub>VDD</sub> - 0.8			V
	, enage	I <sub>OH</sub> = 14mA, pin drive x4 <sup>(2)</sup>					
			load = 10pF, pin drive $x1^{(2)}$			30	
			load = 10pF, pin drive $x2^{(2)}$			50	
		N 2 0 V	load = 10pF, pin drive $x4^{(2)}$			60	
		$V_{VDD} = 3.0 V$	load = $30 \text{ pF}$ , pin drive $x1^{(2)}$			15	
			load = $30 \text{ pF}$ , pin drive $x2^{(2)}$			25	
4	Output frequency (3)		load = $30 \text{ pF}$ , pin drive $x4^{(2)}$			40	
IMAX	Output frequency.		load = 10pF, pin drive $x1^{(2)}$			45	MHZ
			load = 10pF, pin drive $x2^{(2)}$			65	
			load = 10pF, pin drive $x4^{(2)}$			85	
		v <sub>VDD</sub> =4.5 v	load = $30 \text{ pF}$ , pin drive $x1^{(2)}$			20	
			load = 30pF, pin drive $x2^{(2)}$			40	
			load = $30 \text{ pF}$ , pin drive $x4^{(2)}$			60	



Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			12	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 5V,$			5	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 3V,$			4	LSB
	Offset error	ADCFIA.SEQCFGn.SRES = 0	-20		20	mV
	Gain error	(F <sub>adc</sub> = 1.5MHz)	-30		30	mV

 Table 7-31.
 ADC Transfer Characteristics (Continued)12-bit Resolution Mode<sup>(1)</sup>

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain.

 Table 7-32.
 ADC Transfer Characteristics 10-bit Resolution Mode<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			10	Bit
INL	Integral Non-Linearity	V <sub>VDDANA</sub> = 3V,			1.25	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 1V,$			1.25	LSB
	Offset error	ADCFIA.SEQCFGn.SRES = 1 (F <sub>adc</sub> = 1.5MHz)	-10		10	mV
	Gain error		-20		20	mV
RES	Resolution	Differential mode,			10	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 5V,$			1.25	LSB
DNL	Differential Non-Linearity	V <sub>ADCREF0</sub> = 3V,			1.25	LSB
	Offset error	ADCFIA.SEQCFGn.SRES = 1	-20		20	mV
	Gain error	$(F_{adc} = 1.5MHz)$	-25		25	mV

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain.

 Table 7-33.
 ADC Transfer Characteristics 8-bit Resolution Mode<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			8	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 3V,$			0.3	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 1V,$			0.3	LSB
	Offset error	$\begin{array}{c} & \\ & \\ & \\ & \\ & \\ & \\ & \\ & \\ & \\ & $	-10		10	mV
	Gain error		-20		20	mV
RES	Resolution	Differential mode,			8	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 5V,$			0.3	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 3V,$			0.25	LSB
	Offset error		-25		25	mV
	Gain error	(1 <sub>adc</sub> = 1.500112)	-25		25	mV

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain.



Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			12	Bit
INL	Integral Non-Linearity	V <sub>VDDANA</sub> = 3V,			6	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 1V,$			5	LSB
	Offset error	ADCFIA.SEQCFGn.SRES = 0,	-10		10	mV
	Gain error	-30		30	mV	
RES	Resolution	Differential mode,			12	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 5V,$			6	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 3V,$			4	LSB
	Offset error	= ADCFIA.SEQCFGn.SRES = 0,	-15		15	mV
	Gain error	$(F_{adc} = 1.5MHz)$	-30		30	mV

## **Table 7-34.** ADC and S/H Transfer Characteristics 12-bit Resolution Mode and S/H gain = $1^{(1)}$

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain.

Table 7-35.	ADC and S/H Transfer Characteristics 12-b	it Resolution Mode and S/H gain from 1 to 8 <sup>(1)</sup>
-------------	---	--

Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			12	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 3V,$			30	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 1V,$			30	LSB
	Offset error	Offset error       ADCFIA.SEQCFGn.SRES = 0,         Scain error       S/H gain from 1 to 8         Gain error       (F <sub>adc</sub> = 1.2MHz)	-10		10	mV
	Gain error		-25		25	mV
RES	Resolution	Differential mode,			12	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 5V,$			10	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 3V,$			15	LSB
	Offset error	$\begin{array}{l} \hline \qquad \text{ADCFIA.SEQCFGn.SRES} = 0, \\ \hline \qquad \text{S/H gain from 1 to 8} \\ (F_{adc} = 1.5 \text{MHz}) \end{array}$	-20		20	mV
	Gain error		-30		30	mV

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain

Table 7-36.	ADC and S/H Transfer	<b>Characteristics</b>	10-bit Resolution	Mode and S/H gain from 1	to 16 <sup>(1)</sup>
-------------	----------------------	------------------------	-------------------	--------------------------	----------------------

Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution	Differential mode,			10	Bit
INL	Integral Non-Linearity	$V_{VDDANA} = 3V,$			4	LSB
DNL	Differential Non-Linearity	$V_{ADCREF0} = 1V,$			4	LSB
	Offset error	ADCFIA.SEQUEGN.SRES = 1, S/H gain from 1 to 16	-15		15	mV
	Gain error S/H gain from (F <sub>adc</sub> = 1.5MHz	$(F_{adc} = 1.5 MHz)$	-25		25	mV



Figure 7-4. DAC output



 Table 7-40.
 Transfer Characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Тур	Max	Units
RES	Resolution				12	Bit
INL	Integral Non-Linearity	V <sub>VDDANA</sub> = 3V,			20	LSB
DNL	Differential Non-linearity	V <sub>DACREF</sub> = 2V,			20	LSB
	Offset error	One S/H			80	mV
	Gain error				100	mV
RES	Resolution				12	Bit
INL	Integral Non-Linearity	V <sub>VDDANA</sub> = 5V,			20	LSB
DNL	Differential Non-linearity	V <sub>DACREF</sub> = 3V,			20	LSB
	Offset error	One S/H			120	mV
	Gain error				100	mV

Note: 1. The measures are done without any I/O activity on VDDANA/GNDANA power domain.



AT32UC3C

Figure 7-5. Startup and Reset Time



## 7.9.2 RESET\_N characteristics

Table 7-45.	RESET_	N Clock W	/aveform	Parameters
-------------	--------	-----------	----------	------------

Symbol	Parameter	Condition	Min.	Тур.	Max.	Units
t <sub>RESET</sub>	RESET_N minimum pulse length		2 * T <sub>RCSYS</sub>			clock cycles



## 7.9.4.2 Slave mode



Figure 7-13. SPI Slave Mode With (CPOL= 0 and NCPHA= 1) or (CPOL= 1 and NCPHA= 0)

Figure 7-14. SPI Slave Mode With (CPOL= NCPHA= 0) or (CPOL= NCPHA= 1)



Figure 7-15. SPI Slave Mode NPCS Timing





Symbol	Parameter	Conditions	Min	Max	Units
SPI6	SPCK falling to MISO delay			31	ns
SPI7	MOSI setup time before SPCK rises		0		ns
SPI8	MOSI hold time after SPCK rises		7		ns
SPI9	SPCK rising to MISO delay			32	ns
SPI10	MOSI setup time before SPCK falls	external	1.5		ns
SPI11	MOSI hold time after SPCK falls	capacitor =	5		ns
SPI12	NPCS setup time before SPCK rises		4		ns
SPI13	NPCS hold time after SPCK falls		2.5		ns
SPI14	NPCS setup time before SPCK falls		3.5		ns
SPI15	NPCS hold time after SPCK rises		2.5		ns

**Table 7-49.**SPI Timing, Slave Mode<sup>(1)</sup>

Note: 1. These values are based on simulation and characterization of other AVR microcontrollers manufactured in the same process technology. These values are not covered by test limits in production.

#### Maximum SPI Frequency, Slave Input Mode

The maximum SPI slave input frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(f_{CLKSPI}, \frac{1}{SPIn})$$

Where *SPIn* is the MOSI setup and hold time, SPI7 + SPI8 or SPI10 + SPI11 depending on CPOL and NCPHA. $f_{CLKSPI}$  is the maximum frequency of the CLK\_SPI. Refer to the SPI chapter for a description of this clock.

## Maximum SPI Frequency, Slave Output Mode

The maximum SPI slave output frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(f_{PINMAX}, \frac{1}{SPIn + t_{SETUP}})$$

Where *SPIn* is the MISO delay, SPI6 or SPI9 depending on CPOL and NCPHA.  $t_{SETUP}$  is the SPI master setup time. Please refer to the SPI masterdatasheet for  $t_{SETUP}$ .  $f_{PINMAX}$  is the maximum frequency of the SPI pins. Please refer to the I/O Pin Characteristics section for the maximum frequency of the pins.

## 7.9.5 TWIM/TWIS Timing

Figure 7-50 shows the TWI-bus timing requirements and the compliance of the device with them. Some of these requirements ( $t_r$  and  $t_f$ ) are met by the device without requiring user intervention. Compliance with the other requirements ( $t_{HD-STA}$ ,  $t_{SU-STA}$ ,  $t_{SU-STO}$ ,  $t_{HD-DAT}$ ,  $t_{SU-DAT-I2C}$ ,  $t_{LOW-I2C}$ ,  $t_{HIGH}$ , and  $f_{TWCK}$ ) requires user intervention through appropriate programming of the relevant



## 8. Mechanical Characteristics

## 8.1 Thermal Considerations

## 8.1.1 Thermal Data

Table 8-1 summarizes the thermal resistance data depending on the package.

Symbol	Parameter	Condition	Package	Тур	Unit
$\theta_{JA}$	Junction-to-ambient thermal resistance	No air flow	QFN64	20.0	°C ///
$\theta_{JC}$	Junction-to-case thermal resistance		QFN64	0.8	-C/W
$\theta_{JA}$	Junction-to-ambient thermal resistance	No air flow	TQFP64	40.5	°C ///
$\theta_{\text{JC}}$	Junction-to-case thermal resistance		TQFP64	8.7	-C/W
$\theta_{JA}$	Junction-to-ambient thermal resistance	No air flow	TQFP100	39.3	°C ///
$\theta_{JC}$	Junction-to-case thermal resistance		TQFP100	8.5	-C/W
$\theta_{JA}$	Junction-to-ambient thermal resistance	No air flow	LQFP144	38.1	0000
$\theta_{\text{JC}}$	Junction-to-case thermal resistance		LQFP144	8.4	°C/W

 Table 8-1.
 Thermal Resistance Data

## 8.1.2 Junction Temperature

The average chip-junction temperature, T<sub>J</sub>, in °C can be obtained from the following:

1. 
$$T_J = T_A + (P_D \times \theta_{JA})$$
  
2.  $T_J = T_A + (P_D \times (\theta_{HEATSINK} + \theta_{JC}))$ 

where:

- $\theta_{JA}$  = package thermal resistance, Junction-to-ambient (°C/W), provided in Table 8-1 on page 89.
- $\theta_{JC}$  = package thermal resistance, Junction-to-case thermal resistance (°C/W), provided in Table 8-1 on page 89.
- $\theta_{HEAT SINK}$  = cooling device thermal resistance (°C/W), provided in the device datasheet.
- P<sub>D</sub> = device power consumption (W) estimated from data provided in the section "Power Consumption" on page 50.
- T<sub>A</sub> = ambient temperature (°C).

From the first equation, the user can derive the estimated lifetime of the chip and decide if a cooling device is necessary or not. If a cooling device is to be fitted on the chip, the second equation should be used to compute the resulting average chip-junction temperature  $T_J$  in °C.



## Fix/Workaround

None.

## 3 In host mode, the disconnection during OUT transition is not supported

In USB host mode, a pipe can not work if the previous USB device disconnection has occurred during a USB transfer.

## Fix/Workaround

Reset the USBC (USBCON.USB=0 and =1) after a device disconnection (UHINT.DDISCI).

## 4 In USB host mode, entering suspend mode can fail

In USB host mode, entering suspend mode can fail when UHCON.SOFE=0 is done just after a SOF reception (UHINT.HSOFI).

## **Fix/Workaround**

Check that UHNUM.FLENHIGH is below 185 in Full speed and below 21 in Low speed before clearing UHCON.SOFE.

# 5 In USB host mode, entering suspend mode for low speed device can fail when the USB freeze (USBCON.FRZCLK=1) is done just after UHCON.SOFE=0. Fix/Workaround

When entering suspend mode (UHCON.SOFE is cleared), check that USBFSM.DRDSTATE is not equal to three before freezing the clock (USBCON.FRZCLK=1).

## 10.1.11 WDT

## 1 WDT Control Register does not have synchronization feedback

When writing to the Timeout Prescale Select (PSEL), Time Ban Prescale Select (TBAN), Enable (EN), or WDT Mode (MODE) fieldss of the WDT Control Register (CTRL), a synchronizer is started to propagate the values to the WDT clcok domain. This synchronization takes a finite amount of time, but only the status of the synchronization of the EN bit is reflected back to the user. Writing to the synchronized fields during synchronization can lead to undefined behavior.

## Fix/Workaround

-When writing to the affected fields, the user must ensure a wait corresponding to 2 clock cycles of both the WDT peripheral bus clock and the selected WDT clock source.

-When doing writes that changes the EN bit, the EN bit can be read back until it reflects the written value.

